Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/655,229	CHANG, CHUNG NAN
Examiner	Art Unit
Shin-Hon Chen	2131

SEARCHED					
Class	Subclass	Date	Examiner		
			/		
	/	52.			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
USPAT, PGPUB, JPO, EPO, DERWENT (BRS search)	7/14/2006	S.C.		
Inventor name search for double patenting issue	7/14/2006	S.C.		
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